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USPAS - Fundamentals of Ion Sources 16. Electron Beam Ion Sources/Traps (EBIS/EBIT)

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Content

EBIT/EBIS Ion sources

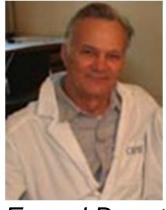
- EBIT Ion Source Fundamentals Brief History
- Key Concepts
- Some examples of Electron Beam Ion Sources (EBIS)
- Main physics processes in the EBIT Source
 - Electron Beam
 - Charge Balance optimizing for the desired charge state
 - Ionization potential and final charge state in an EBIS/EBIT
 - Trap Capacity
 - Vacuum Considerations
- Ion extraction
- (if time) ReAccelerator charge breeder





Electron Beam Ion Sources

- 1967 first proposed developed at about the same time as ECR ion sources (Donets is one of the pioneers)
- Driven by the need to use high charge states to increase the final energy for the accelerator



Evgeni Donets, Dubna

$$LINAC \qquad \frac{E}{M} = \frac{Q}{M} \cdot e \cdot V$$

$$Cyclotrons \qquad \frac{E}{M} = \frac{Q^2}{M} \cdot K, K = \frac{(B \cdot \rho \cdot e)^2}{2}$$

- Readings and materials for the lecture
 - Currell, F. and G. Fussmann, Physics of Electron Beam Ion Traps and Sources. IEEE Transactions on plasma science, 2005. 33(6).
 - G. Zschornack, M. Schmidt, and A. Thorn, Electron Beam Ion Sources, in CAS CERN Accelerator School, Ion Sources. 2013, CERN-2013-007.
 - Donets, E.D., Electron Beam Ion Sources, in The Physics and Technology of Ion Sources.
 1989, I. Brown, Wiley-VCH Verlag GmbH & Co. KGaA.
 - Wenander, F.J.C., Charge Breeding of Radioactive Ions, in CAS CERN Accelerator School, Ion Sources. 2013, CERN-2013-007.
 - Wenander: RexEBIT http://cds.cern.ch/record/478399/files/open-2000-320.pdf?version=1





Key Concepts – physical basis of operations

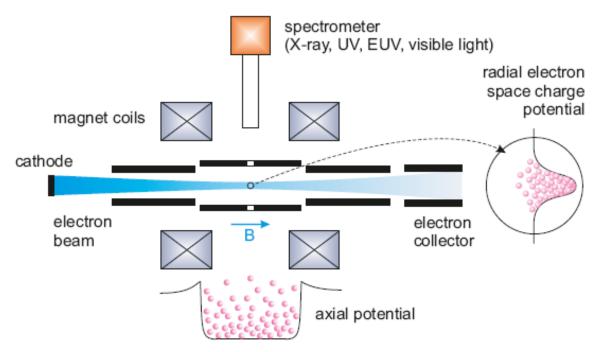
- Production of an extended electron beam of a given energy (Ionization Energy!, High electron density!)
- 2) Creation of an electrostatic trap for the ions while they get ionized by step-by-step ionization (Confinement Time!)
- Injection of a defined number of low charge state ions or injection of neutrals into the trap (vapor/gas)
- Extraction of the ions when the desired charge state is reached (pulsed operation - mostly)
- 5) Electron dump (collector): controlled way to dump the electron beam after it passes through the trap

EBIS do not operate with a plasma discharge!





EBIT Ion sources – main concept



Electron beam	radial confinement and breeding – successive electron impact ionization
Magnetic field	compression of electron beam
Trap electrodes	axial confinement





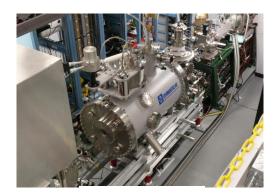
EBIT overview

- Development today: family of ion sources, warm magnets, permanent magnets, superconducting
- Atomic physics groups, x-ray generator, calibration, spectroscopy
- Injector for synchrotrons: RHIC
- Charge Breeder for post –accelerators (Rex-Isolde (CERN), CARIBU (ATLAS, ANL), ReA (FRIB/NSCL, MSU))

Superconducting magnets

Permanent magnet





ReA EBIT

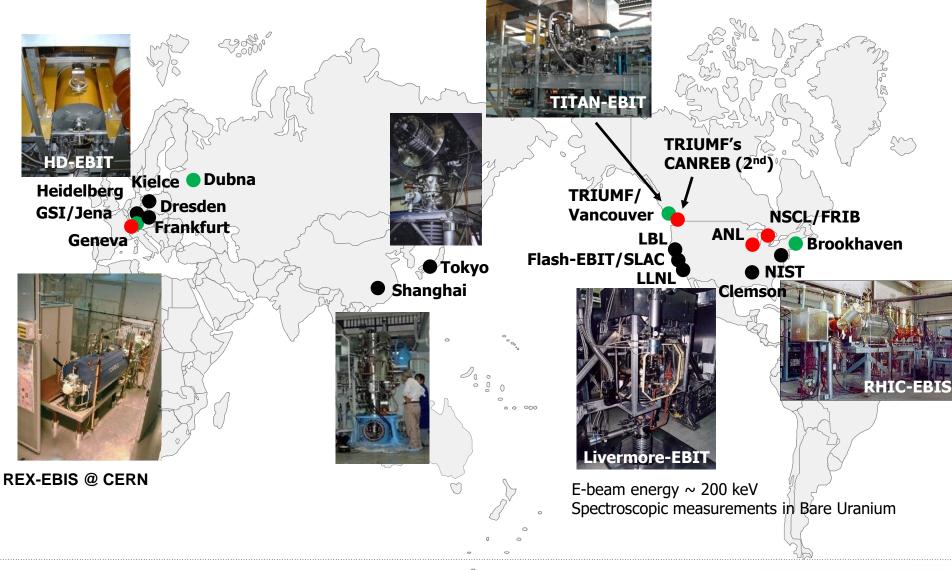








Many EBIS/T around the world...







RHIC: Relativistic Heavy Ion Accelerator (collider)



- 2 independent intersecting storage rings with 6 interaction points
- Can circulate heavy ions or protons

Chain of accelerators

- 3 injectors (High charge state injector (EBIS source+linac), Tandem injector, proton linac)
- Booster Synchrotron
- Alternating Gradient Synchrotron
- 2.4 miles circumference storage ring

EBIS is an ideal source for synchrotrons because of the sharp pulse structure of the beam produced





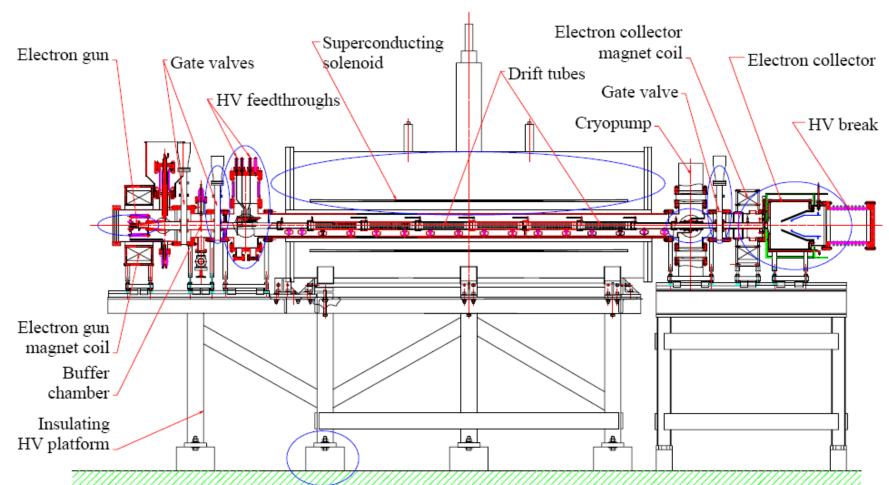
EBIS test stand facility at RHIC







BNL EBIT cross Section

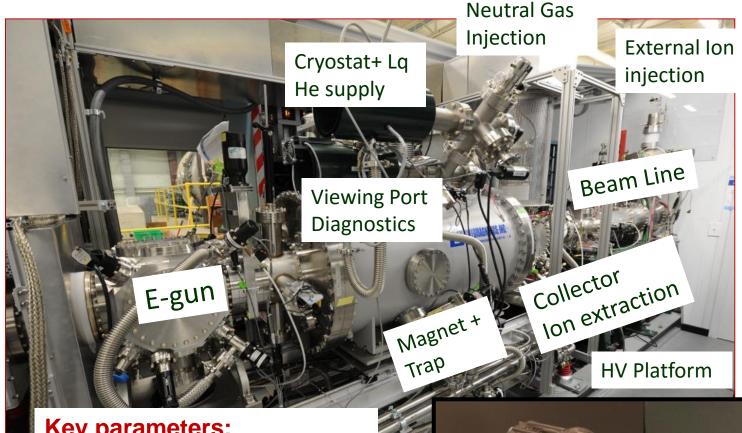


https://www.bnl.gov/cad/accelerator/docs/pdf/EBISDesignReportl.pdf





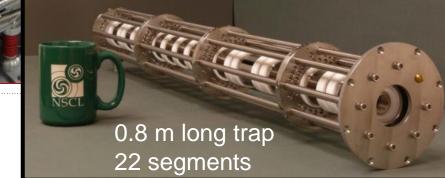
ReA EBIT Charge Breeder



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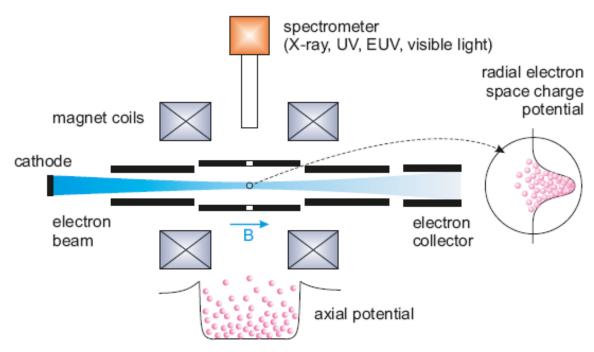


- Magnetic field: B=6T,
- Electron current: I_e=0.5 ... 5 A,
- Electron energy: E_e < 30 keV
- Current density: j ~ 10⁴ A / cm²
- Trap Length: 635 mm





EBIT Ion sources – main concept

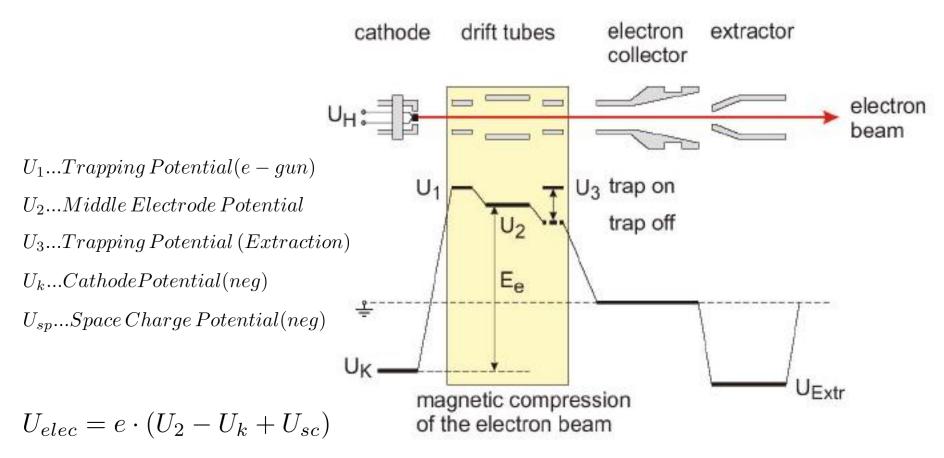


Electron beam	radial confinement and breeding – successive electron impact ionization
Magnetic field	compression of electron beam
Trap electrodes	axial confinement





EBIT Ion sources – main concept

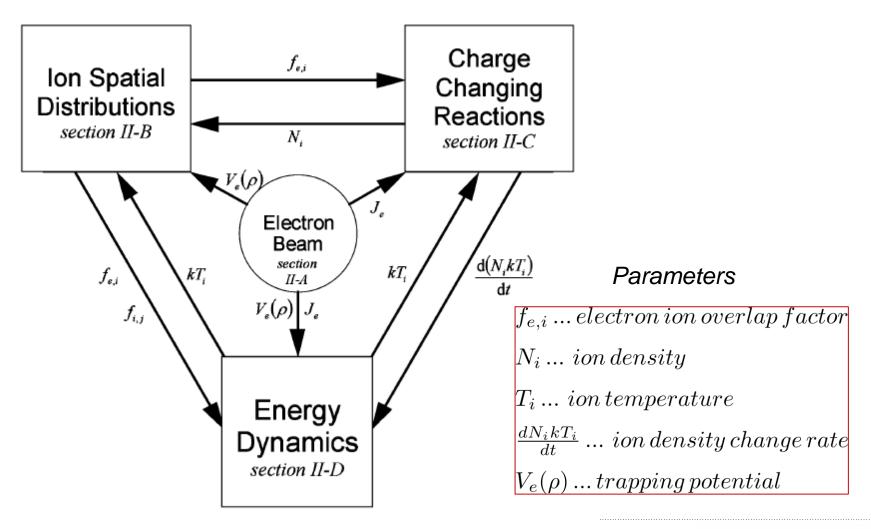


 $U_{elec} \, ranges \, from \, 500 \, eV \, to \, 200 \, keV$

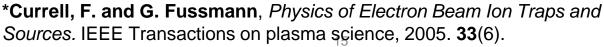




Summary of relationships of processes in an EBIS/T*









EBIS: Main Processes

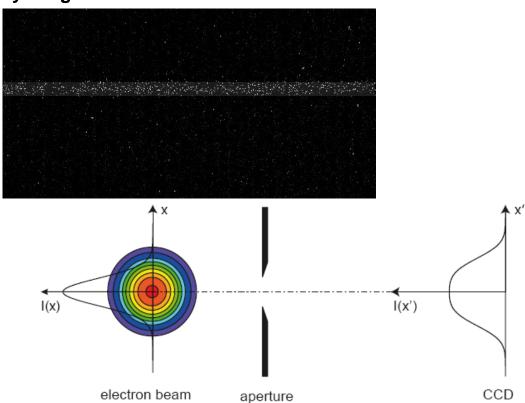
The electron beam drives all atomic physics processes and are all interrelated

- Charge Dynamics Processes which lead to trapped ions being created, changing charge state or lost from the trap
- Energy Dynamics Processes that change the characteristic temperature of the ions in the trap (kT_i)
- Ion Spatial Distribution Location of trapped ions (one for each charge state)
 - Need to define an overlap function between the electron beam and the ion cloud, driven by ion temperature!





X-ray image of the electron beam in the ReA EBIT



Electron Beam





Electron Beam/ Radial Confinement

- Ideal flow (Brillouin Flow) is established by a nearly parallel beam, with $T_e = 0$, $B_{cathode} = 0$
- Shape of the cathode is optimized to counteract the space charge of the electron beam (e.g Pierce angle)
- Upper limit for compression is given by the Brillouin Radius

$$r_b[\mu m] = \frac{150}{B[T]} \sqrt{\frac{I_e[A]}{\sqrt{E_e[keV]}}}$$

Adding T_e, B_{cathode} → Herrmann Radius (see original paper for derivation)

$$r_h = r_b \sqrt{\frac{1}{2} + \frac{1}{2} \sqrt{1 + 4(\frac{8kT_c r_c^2 m}{e^2 r_b^4 B^2} + \frac{B_c^2 r_c^4}{B^2 r_b^4})}}$$
 80% of the beam is within r_h

Typical beam sizes are 30 to 100 µm





Radial Trapping potential

$$V_{\rm e}(r) = \left\{ \begin{array}{ll} \frac{U_{\rm e} r^2}{r_{\rm e}^2} & \text{for } r < r_{\rm e}, \quad \text{Potential inside the electron beam} \\ U_{\rm e} \left(2 \ln \frac{r}{r_{\rm e}} + 1 \right) & \text{for } r > r_{\rm e}. \quad \text{Potential outside the electron beam} \end{array} \right.$$

$$U_{\rm e} = \frac{I_{\rm e}}{4\pi\varepsilon_0 v_{\rm e}} = \frac{1}{4\pi\varepsilon_0} \sqrt{\frac{m_{\rm e}}{2}} \frac{I_{\rm e}}{\sqrt{E_{\rm e}}}. \qquad \text{Total charge/unit lengths of the trap}$$

$$U_{\rm e}\left({\rm V}\right) = \frac{30I\left({\rm A}\right)}{\sqrt{1 - \left(\frac{E_{\rm e}\left({\rm keV}\right)}{511} + 1\right)^{-2}}}\cdot \quad \text{Convenient calculating tool}$$

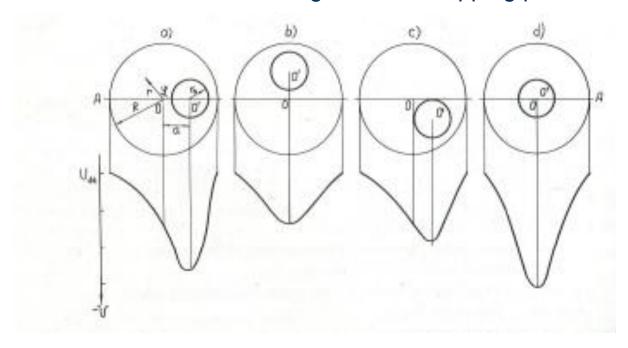
The trapping potential is partially compensated by the ion cloud





Additional variation for the trapping potential are being caused by misalignment of the magnet to the drift tube

If the drift tubes are misaligned – the trapping potential is reduced



Donets, E.D., *Electron Beam Ion Sources*, in *The Physics and Technology of Ion Sources*. 1989, I. Brown, Wiley-VCH Verlag GmbH & Co. KGaA

Wenander: RexEBIT http://cds.cern.ch/record/478399/files/open-2000-320.pdf?version=1





Radial trapping potential and electron ion overlap function

 The trapping potential is partially compensated by the ion cloud

$$V(\rho) = V_e(\rho) + \sum_{i,\alpha} V_i(\rho)$$

Sum over all ions with i the CS and α the ion species

The ion distribution of the electron beam can be described by a Boltzmann distribution

$$n_i(\rho) = n_i(0)e^{-(q_iV(\rho)/kT_i)}$$

$$\begin{array}{ccc} \bullet & \text{Now we can calculate } \textit{V(p)} & & \frac{1}{\rho}\frac{\partial}{\partial\rho}\left(\rho\frac{\partial V(\rho)}{\partial\rho}\right) = \Theta(r_e-\rho)\left(\frac{4V_0}{r_e^2}\right) \\ & & -\frac{1}{\varepsilon_0}\sum_i q_i n_i(0)\exp\left(-\frac{q_i V(\rho)}{kT_i}\right) \end{array}$$

 The spatial distribution leads to the definition of an overlap function between the ions and the electron beam – which defines the probability of ionization

$$f_{e,i} = \frac{N_i^{in}}{N_i}$$

N_i is proportional to the ion temperature! Hotter ions will spend less time in the beam!





Overlap function for ions injected into the EBIT can be tricky

- If an external beam is injected into the EBIT(as 1+ or 2+ beam) the alignment of the beam in respect to the electron cloud is critical
- If the ions are spending part of the time outside of the e-beam the effective electron density will be reduced

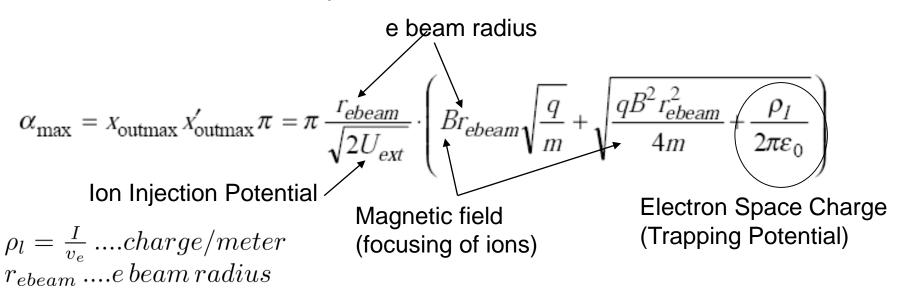




into the electron cloud

Overlap function for ions injected into the EBIT

- If the beam is injected from the outside (as 1+ or 2+ beam) the alignment of the beam in respect to the electron cloud is critical
- If the ions are spending part of the time outside of the e-beam the effective electron density will be reduced
- Can define an EBIS acceptance





Wenander: RexEBIT http://cds.cern.ch/record/478399/files/open-2000-320.pdf?version=1

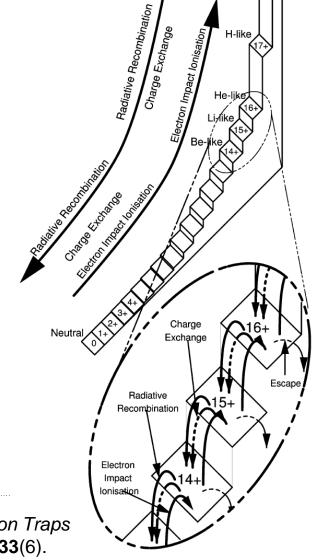


Ionization Balance in the EBIT Trap

 Ionization through electron impact (step-by-step) until charge state balance is reached
 Charge generation processes x charge destructive processes

Main Atomic processes are

- 1. Electron Impact Ionization
- 2. Charge Exchange
- 3. Radiative Recombination
- Multiple collisions are required the ionization time must be long enough to reach desired charge state
- Losses must be controlled to allow reaching the desired charge state
- Vacuum level must be controlled to minimize charge exchange and trap loading by residual gas





*Currell, F. and G. Fussmann, Physics of Electron Beam Ion Traps and Sources. IEEE Transactions on plasmæscience, 2005. **33**(6).

Charge evolution – ionization balance

The charge evolution can be described through a set of coupled differential equations

$$\begin{split} \frac{dN_{i}}{dt} &= \frac{J_{e}}{e} \cdot (N_{i-1} \cdot \sigma_{i-1}^{EI} \cdot f_{e,i-1} - N_{i} \cdot \sigma_{i}^{EI} \cdot f_{e,i}) \\ &+ \frac{J_{e}}{e} \cdot (N_{i+1} \cdot \sigma_{i+1}^{RR} \cdot f_{e,i+1} - N_{i} \cdot \sigma_{i}^{RR} \cdot f_{e,i}) \\ &+ n_{0} \cdot (N_{i+1} \cdot < \sigma_{i+1}^{CX} \cdot v > \cdot f_{e,i-1} - N_{i} \cdot < \sigma_{i}^{CX} \cdot v >) \\ &- (N_{i} \cdot R_{i}^{Esc}) \end{split}$$

EI... Electron Impact Ionization

RR... Radiative Recombination

CX... Charge Exchange

 R_i^{Esc} ... Rate of Ion Loss

For a single species:

2(i+1) coupled differential equations!

i+1 charge dynamics

i+1 energy dynamics

Realistic simulation models are complex - but general guideline for performance can be derived by simplified estimates and upper limits



Electron Impact Ionization

$$X^{q+} + e^- \rightarrow X^{(q+1)+} + 2e^-$$

$$\frac{J_e}{e} \cdot (N_{i-1} \cdot \sigma_{i-1}^{EI} \cdot f_{e,i-1} - N_i \cdot \sigma_i^{EI} \cdot f_{e,i})$$

Ionization Potentials

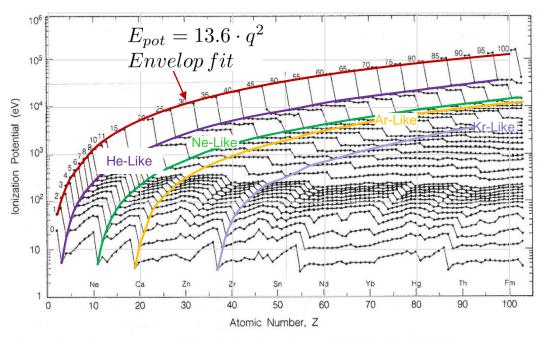


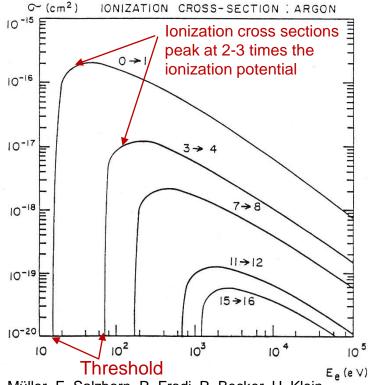
Figure 2.3 Ionization potentials for multiply charged ions of all of the elements [15].

$$\sigma_{i,i+1} = 1.4 \cdot 10^{-13} \frac{\ln \frac{E_e}{E_i}}{E_e E_i} (eV)^2 cm^2$$

E_e: E-beam energy

E_i: Ionization potential





A. Müller, E. Salzborn, R. Frodi, R. Becker, H. Klein,

and H. Winter, J. Phys., 1980. B 13: p. 1877.



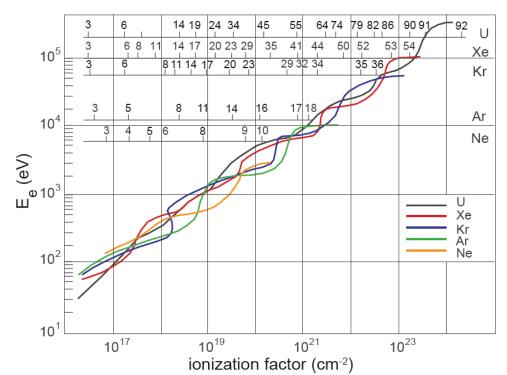
Ionization Factor: Product of the electron flux and the

time of bombardment

Probability for Ionization:

$$P_{q \to q+1} = \sigma_{q \to q+1} \cdot j_e \cdot \tau_i \to 1$$

$$j_e \cdot \tau_q > \sum_{k=1}^q \frac{e}{\sigma_k^{EI}}$$



with
$$j_e = v_e \cdot n_e \cdot e \dots electron beam density$$

jτ: quality factor/ tuning factor for an EBIT ion source is the combination of the electron density (electron gun current + compression)

Depending on the ionization potential of the desired charge state and electron beam density, the minimum confinement time can be calculated





Ideal production conditions for ions of different isoelectronic sequences.

example electron beam $150 \, mA$, $r = 30 \mu m$, $j_e = 5.3 \cdot 10^3 \frac{A}{cm^2}$

Sequence	Neon $Z = 10$	Argon $Z = 18$	Krypton $Z = 36$	Xenon $Z = 54$	Gold $Z = 79$	Uranium $Z = 92$
Atom fully ionized	Ne^{10+} 2×10^{21} 3 7 ms	Ar ¹⁸⁺ 2×10^{21} 9 67 ms	Kr^{36+} 3 × 10 ²² 40 1 s	Xe^{54+} 2×10^{23} 80 7 s	Au ⁷⁹⁺ 6×10^{23} 180 20 s	U^{92+} $2 \times 10^{24+}$ 300 67 s
Helium- like	Ne^{8+} 8 × 10 ¹⁸ 0.6 0.3 ms	Ar^{16+} 1×10^{20} 2 3 ms	${ m Kr}^{34+} \ 2 imes 10^{21} \ 7 \ 67 \ { m ms}$	Xe^{52+} 2 × 10 ²² 20 0.7 s	Au^{77+} 6×10^{22} 45 2 s	U^{90+} 2×10^{23} 70 7 s
Neon- like		Ar^{8+} 3 × 10 ¹⁸ 0.3 0.1 ms	$Kr^{28+} \\ 3 \times 10^{20} \\ 4 \\ 10 \text{ ms}$	Xe^{44+} 2 × 10 ²¹ 8 67 ms	Au ⁶⁹⁺ 6×10^{21} 17 200 ms	U^{82+} 3×10^{22} 30 1 s
Argon- like			$\mathrm{Kr^{18+}}$ 1 × 10 ¹⁹ 1.5 0.3 ms	Xe^{36+} 2 × 10 ²⁰ 5 7 ms	$\begin{array}{c} {\rm Au^{61+}} \\ {\rm 1\times 10^{21}} \\ {\rm 12} \\ {\rm 33\ ms} \end{array}$	U^{74+} 5×10^{21} 20 167 ms
Krypton- like				Xe^{18+} 6×10^{18} 1 0.4 ms	Au^{43+} 1×10^{20} 4 3 ms	U^{56+} 7×10^{20} 7 23 ms
Xenon- like					Au^{25+} 2 × 10 ¹⁹ 1.5 0.7 ms	U^{38+} 7×10^{19} 4 2 ms

Optimum Electron Energy Confinement Time Required

<u>arXiv:1411.2445</u>; CERN-2013-007 G.Zschornack, et.al



Maximum Capacity of the trap

Key Concepts

- Residual gas pressure
- Compensation
- Pulsed operations

How many particles can be stored?

$$C_{el} = \frac{1}{e} \sqrt{\frac{m_e}{2 \cdot Ee}} I_e L = \frac{I_e L}{v_e}$$

 How many particles can be extracted in one pulse (upper limit for one charge state)

$$N_q = \frac{I_e L}{v_e q}$$

$$R_q \approx \frac{N_q}{\tau_q} \quad with \quad j_e \cdot \tau_q > \sum_{k=1}^q \frac{e}{\sigma_k^{EI}}$$



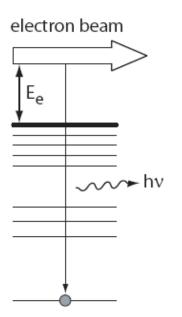


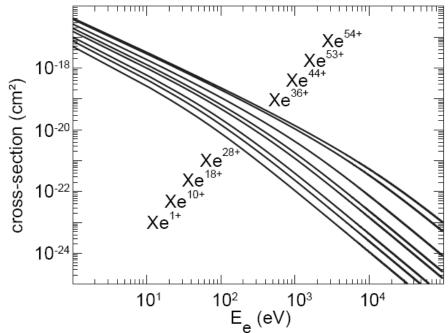
Radiative Recombination Processes

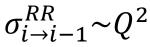
$$\frac{J_e}{e} \cdot (N_{i+1} \cdot \sigma_{i+1}^{RR} \cdot f_{e,i+1} - N_i \cdot \sigma_i^{RR} \cdot f_{e,i})$$

$$X^{q+} + e^{-} \to X^{(q-1)+} + h\omega$$

This cross section decreases with increasing electron energy and increases with charge state









Massachusetts Institute of Technology

Charge Exchange

$$n_0 \cdot (N_{i+1} \cdot \langle \sigma_{i+1}^{CX} \cdot v \rangle \cdot f_{e,i-1} - N_i \cdot \langle \sigma_i^{CX} \cdot v \rangle)$$

$$X^{q+} + X \rightarrow X^{(q-1)+} + X^+$$
 neutral-ion charge exchange

 $n_0 \dots neutral\ gas\ pressure!$

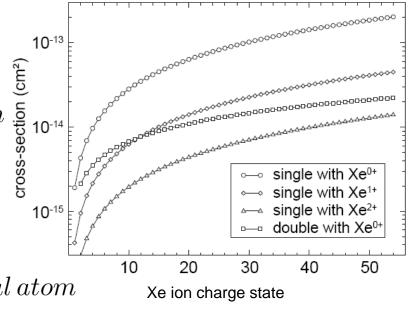
 $v \dots relative \ velocity$

 $\sigma^{CX}_{i+1} \dots charge \ exchange \ cross \ section$

Increases with Charge State!!

$$\sigma^{CX} = 1.43 \cdot 10^{-12} \, \underbrace{q^{1.17}}_{i} \cdot E_i^{-2.76}$$

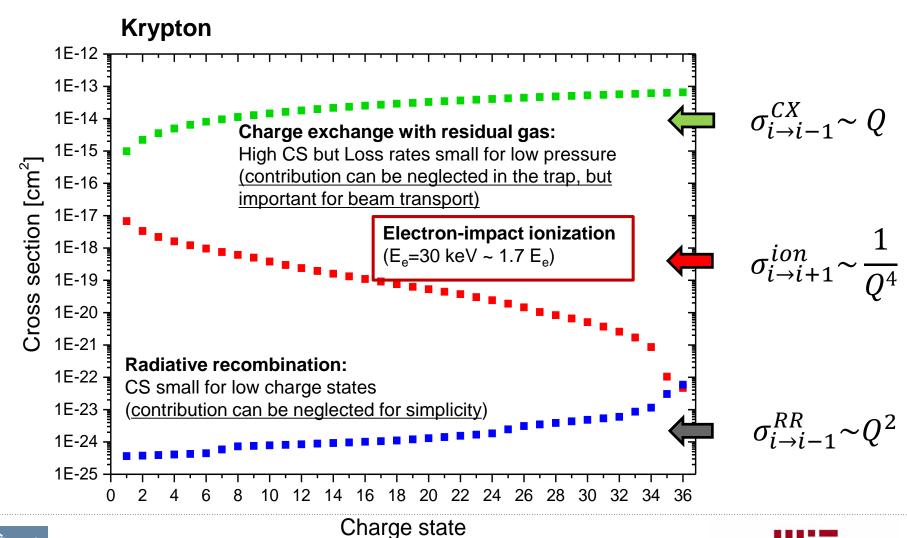
 $E_i \dots Ionization potential of the neutral atom <math>q \dots Charge \, State$







Relative importance of the cross sections in the EBIS

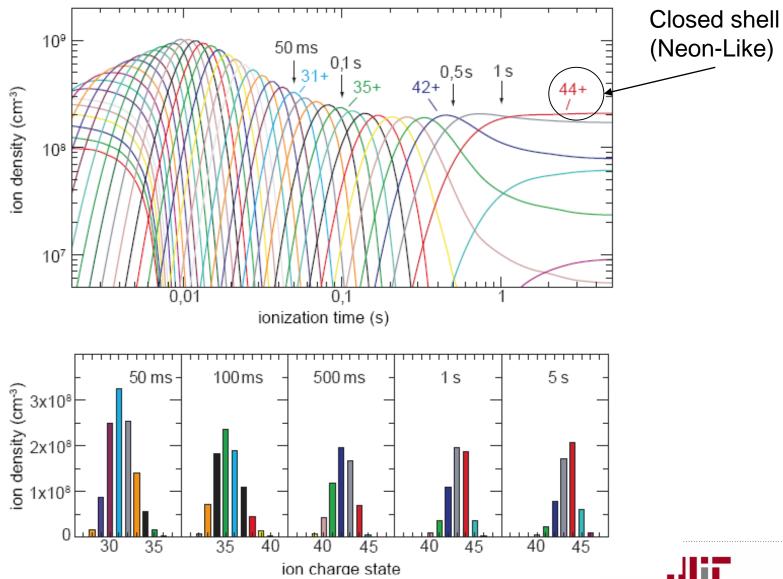




Courtesy: A. Lapierre



Evolution of the ionization of xenon ions in a Dresden EBIT at $E_e = 15 \text{ keV}$, $I_e = 40 \text{ mA}$ and $p = 2 \cdot 10^{-9} \text{ mbar}$.





Ion Losses/Escape from the Trap

Ion-ion collisions lead rapidly to a Maxwell-Boltzmann distribution (ms)

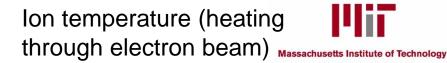
$$f(E_{\rm i}) = \frac{2}{\sqrt{\pi} \ kT_{\rm i}} \sqrt{\frac{E_{\rm i}}{kT_{\rm i}}} \exp\left(-\frac{E_{\rm i}}{kT_{\rm i}}\right)$$

- The formation of a Boltzmann energy distribution has consequences for the whole ion trap process
 - Permanent ion losses At a certain mean ion energy, ions always exist with an energy greater than a critical energy and can leave the trap with the barrier Ub. This means that we have a constant ion loss from the trap: Electron – ion interaction is the main heating source
 - Evaporative cooling of multiply charged ions by light low charge state ions. Elastic collisions between ions with different charge states and masses lead to an equilibrium energy distribution for each ion

$$R_i^{Esc} = \frac{3}{\sqrt{2}} \nu_i \frac{e^{-\omega_i}}{\omega_i} \qquad \omega_i = \frac{q_i V_t}{kT_i} \qquad \text{Trapping Potential}$$



ion-ion collision frequency: temperature exchange





EBIS: Energy Dynamics

- Energy Dynamics Processes that change the characteristic temperature of the ions in the trap (kT_i)
 - The hotter the ions the less time they spend in the trap, the less overlap the have with the electron beam
 - Electron beam is a major source of heating through Landau-Sptzer collisions (increases with CS)
 - Ion trapping increases with charge state higher charge state ions get trapped deeper and can withstand some heating (qeV/kT)
 - Ion-ion collision can be a source of cooling
 - Evaporative cooling: Ions leaving the trap carry energy away from the trap – add lighter gas to the trap or even residual atoms
 Can be used as tuning tool by lowering the extraction trap potential slightly ("leaky" EBIS mode)





Vacuum in the trap – estimate of trap fill time

$$\sigma_{i,i+1} = 1.4 \cdot 10^{-13} \frac{\ln \frac{E_e}{E_i}}{E_e E_i} (eV)^2 cm^2$$

E_e: E-beam energy

E_i: Ionization potential

$$\tau_{trap} = (\sigma_0 n_0 v_e)^{-1}$$

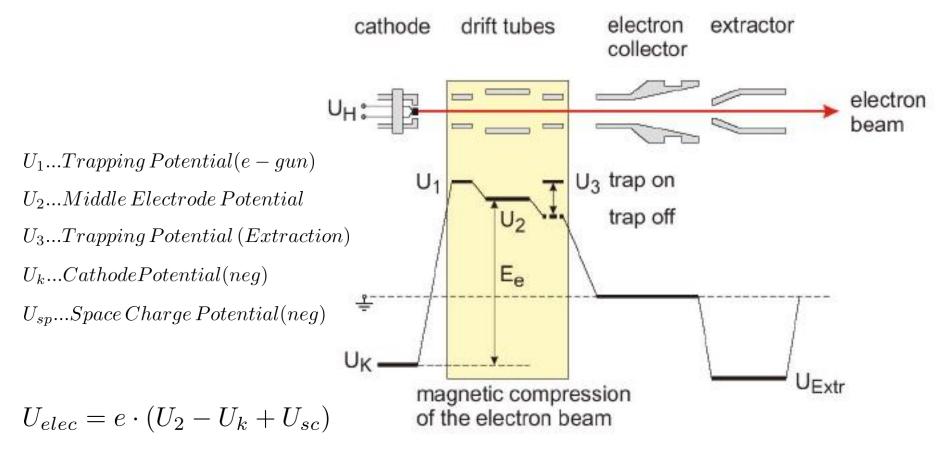
Time to fill up the trap!
Inverse of the reaction rate of the particles in the trap under the electron beam bombardment!

Homework: Assume the residual gas is nitrogen only, using the Lotz formula and considering only $0\rightarrow 1+$ reactions, calculate the time to fill the trap with only residual ions for p=1e-7 mbar, 1e-9mbar, 1e-11mbar, $E_e=20$ keV





Ion beam extraction



 $U_{elec} \, ranges \, from \, 500 \, eV \, to \, 200 \, keV$





Extraction of Ions from the EBIT

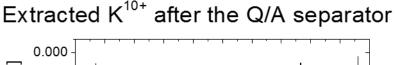
- Permanently open trap: Ions are produced without axial trapping (lowest charge states)
- Partially closed trap leaky mode: lower the extraction potential that a certain number of ions can escape – results in low energy spread ions (only the ones that can overcome the remaining trapping potential (low to medium charge state ions, some high charge state – CW operation)
- Periodically open trap: pulsed operations, highest current for high charge state ions, jt can be controlled!

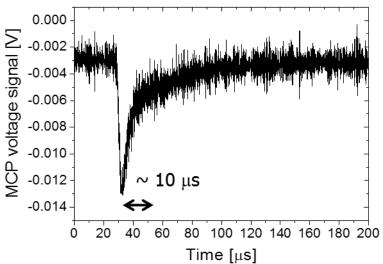




Pulsed extraction can be timed to achieve the needs of the user

- The problem: Opening the trap releases 10⁴-10⁹ ions in 10s of microseconds
 - Great for synchrotrons (e.g BNL)
 - Really bad if delivered to users, typical detector rates are Mz or 10⁶ particles/sec
 - Therefore the pulse needs to be stretched and the release of ions well controlled

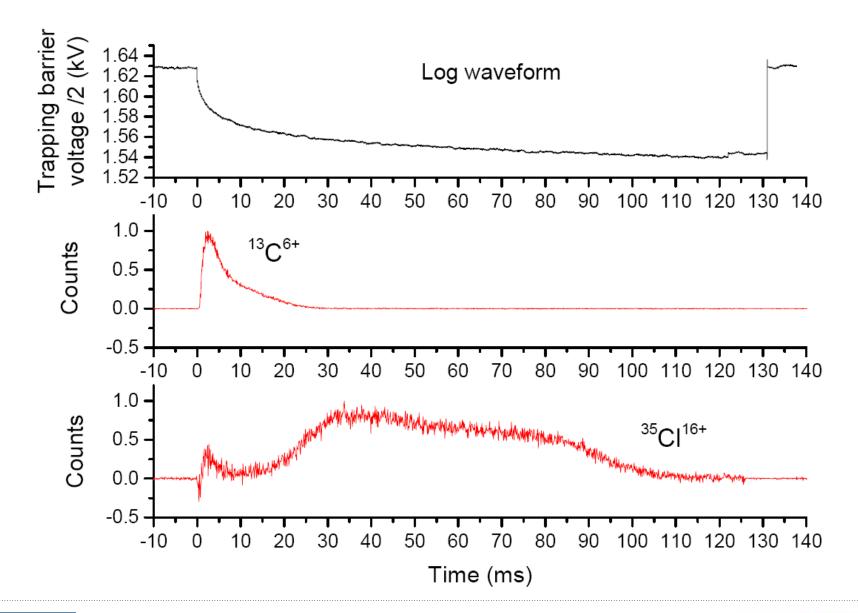




- Possible by shaping the extraction voltage of the ions to release ions in a rate that is suitable for the end-user
- Bonus Advantage: results in narrower energy spread ions as the ions are released at nearly the same energy, which leads to better resolution of the mass spectrum in the beam line











ReAccelerator



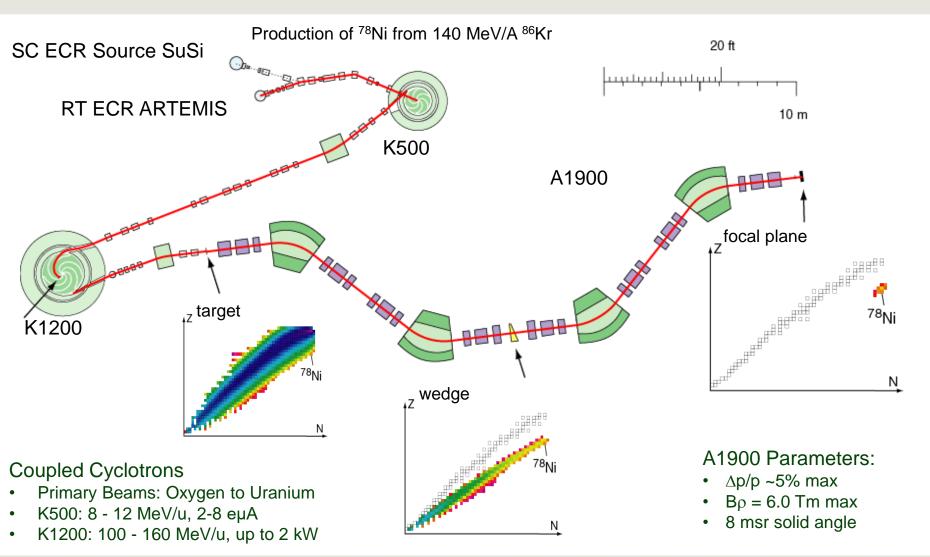


Rare Isotope Facility at MSU 60 100,102-104,106,108,110,112Sn 96,110-119,125-130_{Cd} Proton Number 100-118Ru 4-85,96-112Mo 80-81 91-108_{Zr} 64-70,76-91Se 60-66,72-78,80-86Ge 60,62-63,72,74,76,78-81Zn 48,54-64,67-78Ni 45-46,50-72Fe 39-40,43-63T Observed Low Energy Experiments at CCF 22-24,26-44Si Produced at CCF (observed previously) **Nuclear Physics** Primary Beams status July 2012 **Experimental Area** 20 40 60 80 **Neutron Number** Heavy Ion ReAcceleration Beam Driver Stopping Fragment Separator **Target**



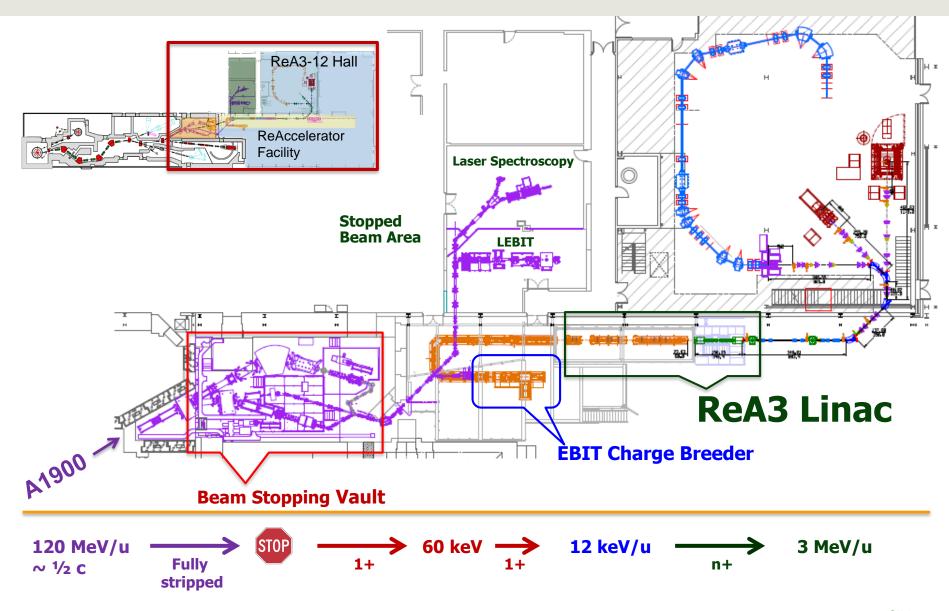


Rare Isotope Beam Production





From Fast To Not-So-Fast



Deceleration Challenge

Why Not A Linac In Reverse?

Transverse emittance → + plus momentum spread ~ 5% ∆p/p

Example:

- Emittance for ⁷⁹Br entering N4:
 - ~40 π mm mrad at 6.875 GeV (eq. 3.1Tm)
- Emittance ~ sqrt(E)
- \rightarrow at 60 keV (transport in stopped beam area) : 340 π mm mrad
- \rightarrow at 2 keV (entrance energy into LEBIT/EBIT) : 1854 π mm mrad

(accepts \sim 40 π mm mrad!)

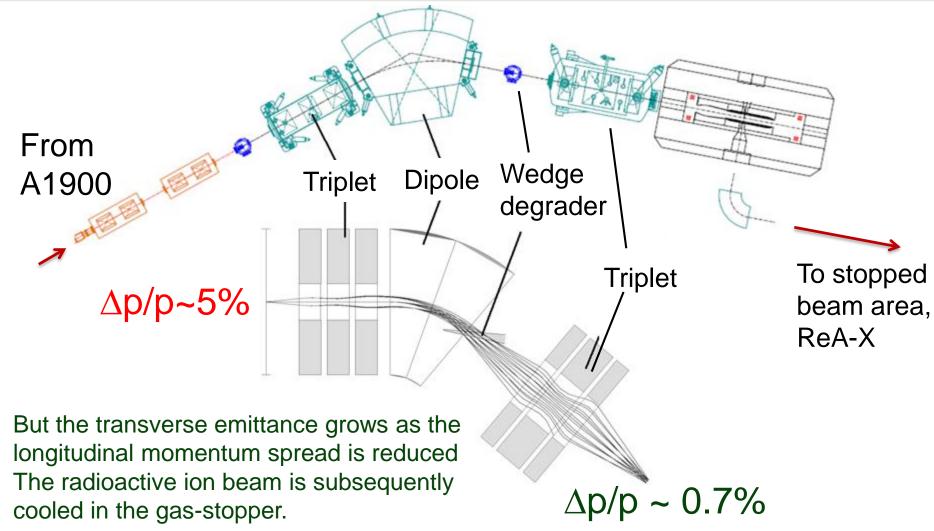
Solution:

- Momentum compression line for the incoming beam
- Dissipation of energy and cooling in solid/gas followed by extraction with an RF drag field
- Particles "forget" their origin





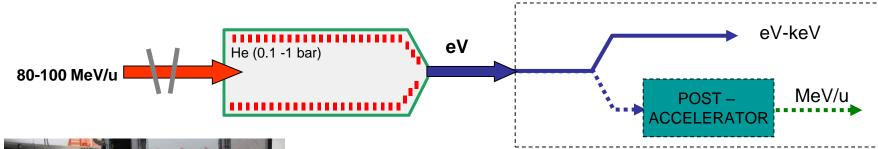
Momentum Compression Line In The Stopping Vault

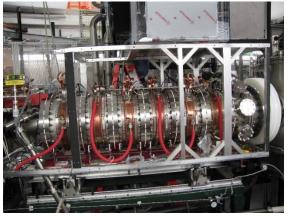


Two Gasstopper Systems Are Under Development

ANL Gas Cell Is Installed In The Vault And Commissioned (2013) Assembly Of The Cyclotron Stopper Is Developed Of Line (2015)

Convert fast-beams produced in projectile fragmentation to low-energy beams:





Linear Gas Stopper

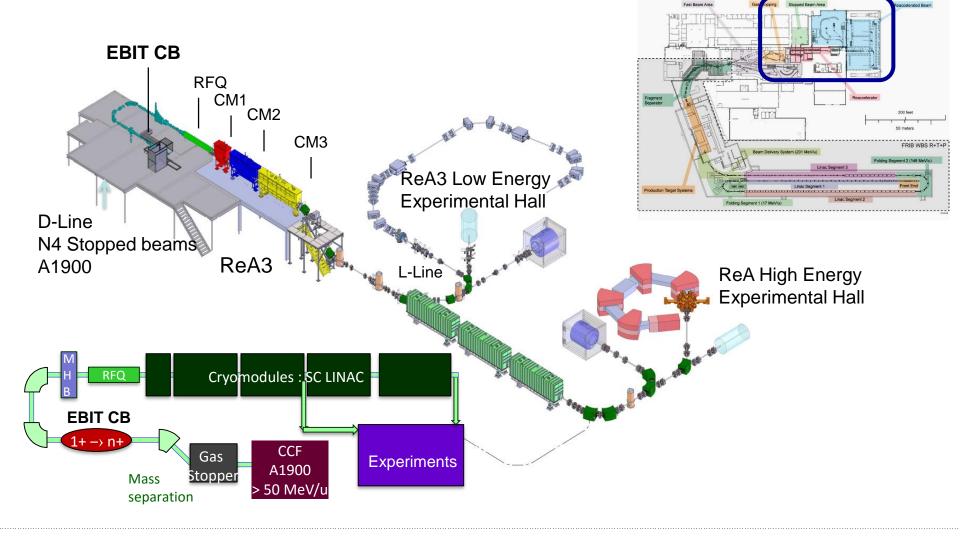
- Concept is proven (ANL, MSU)
- Lots of experience at MSU

Limitations:

- Low efficiency for light ions (stopping range)
- Space charge due to ionization

ANL 1.2 m long linear gas cell
High purity helium: ~ 90 Torr, -5°C
Thermalizes RIB ions to < 1eV
Singly and doubly charged

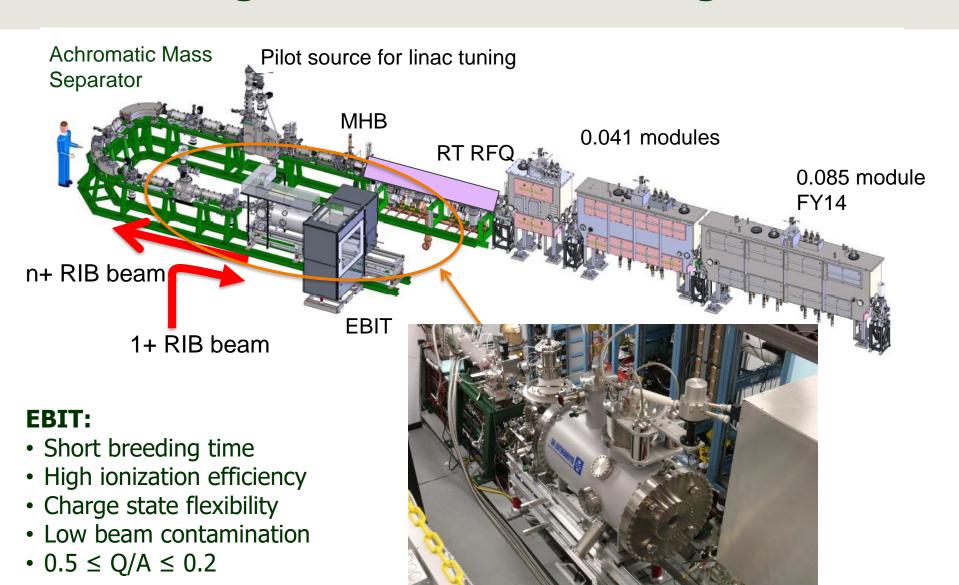
ReA Post-Accelator at MSU



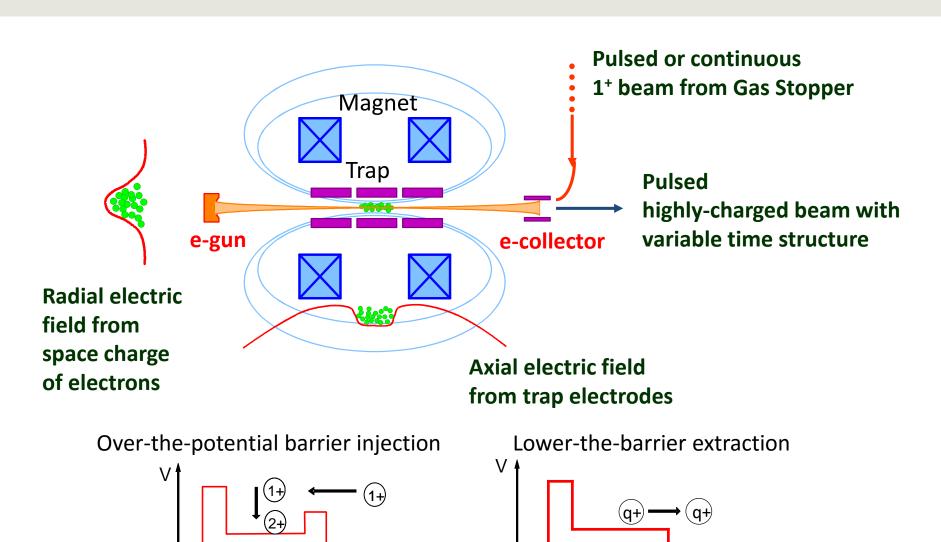




ReA Design Choices: EBIT Charge Breeder



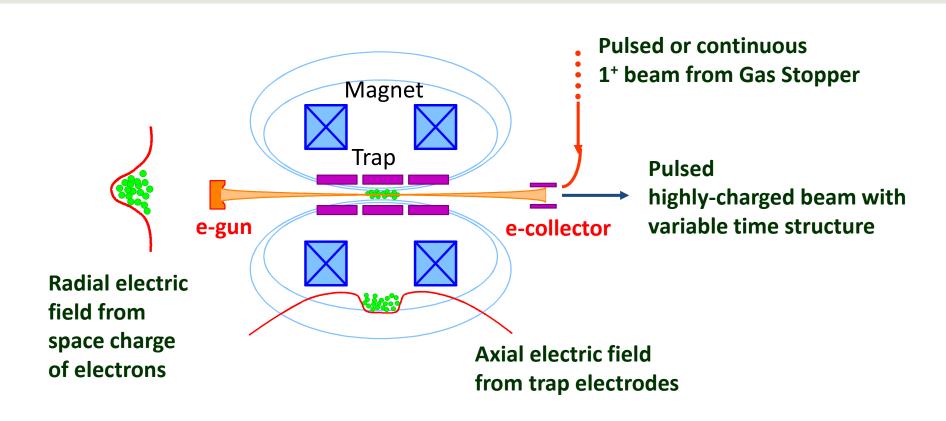
Charge Breeding in the EBIT Source



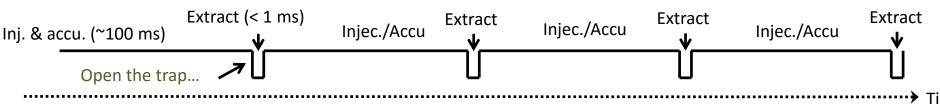
Continuous injection

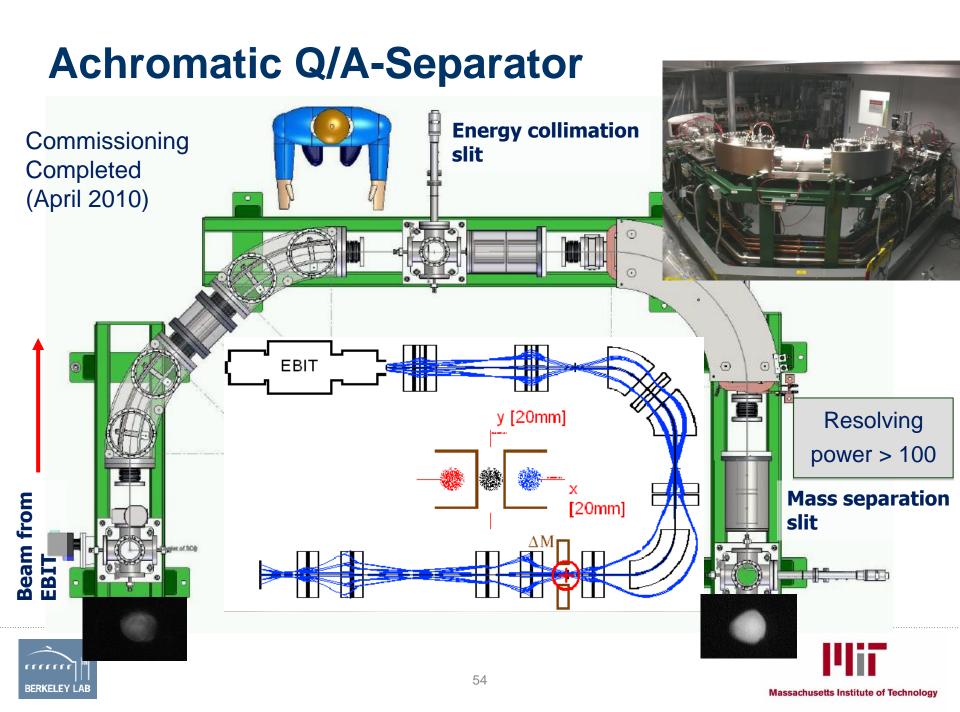
Pulsed extraction

Charge Breeding in the EBIT Source

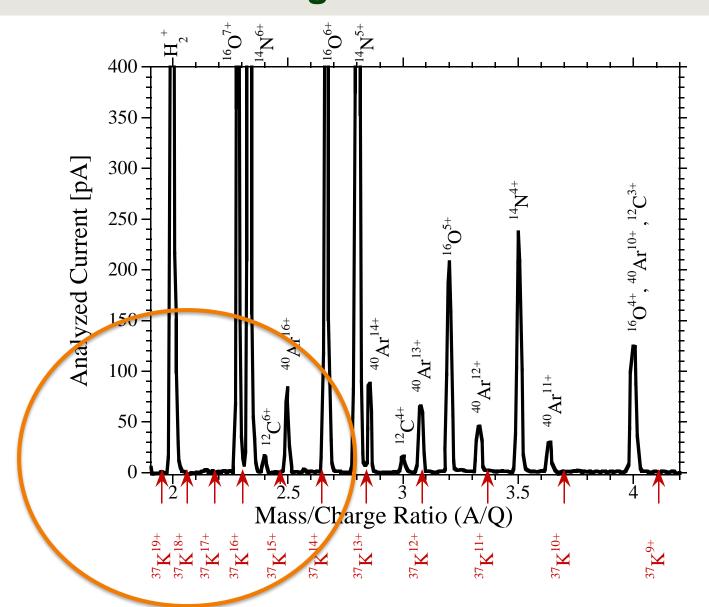




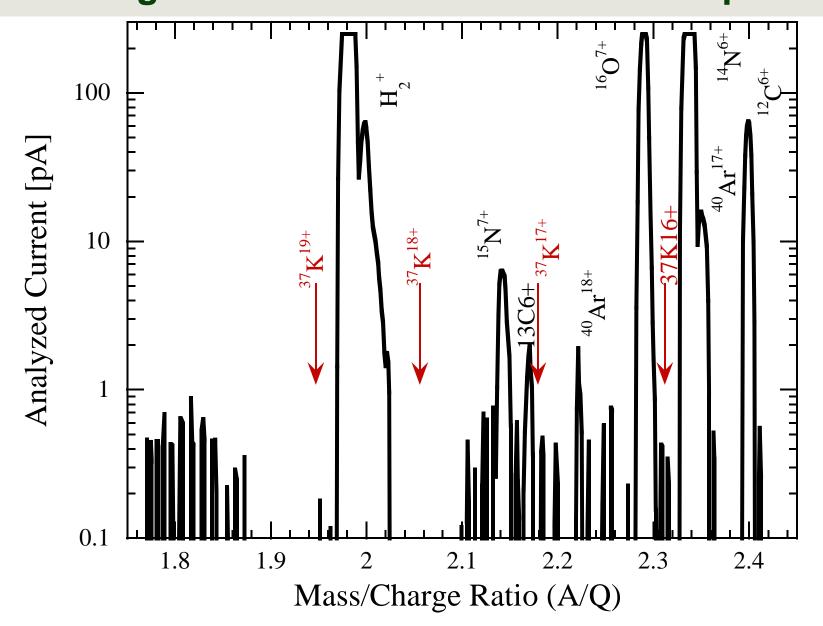




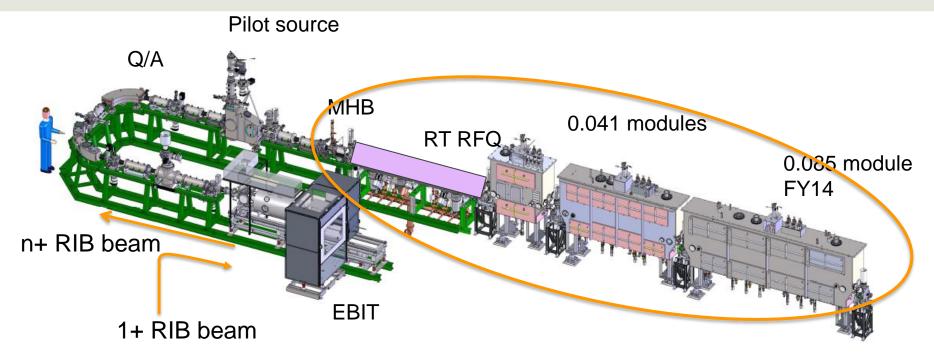
EBIT Background Spectrum And Selection Of ³⁷K Charge States



Background Ions From The Charge Breeder In The Region Of Interest Are Less Than 1 pA



ReA Design Choices: RT-RFQ With External Buncher And High Efficiency SC-Linac

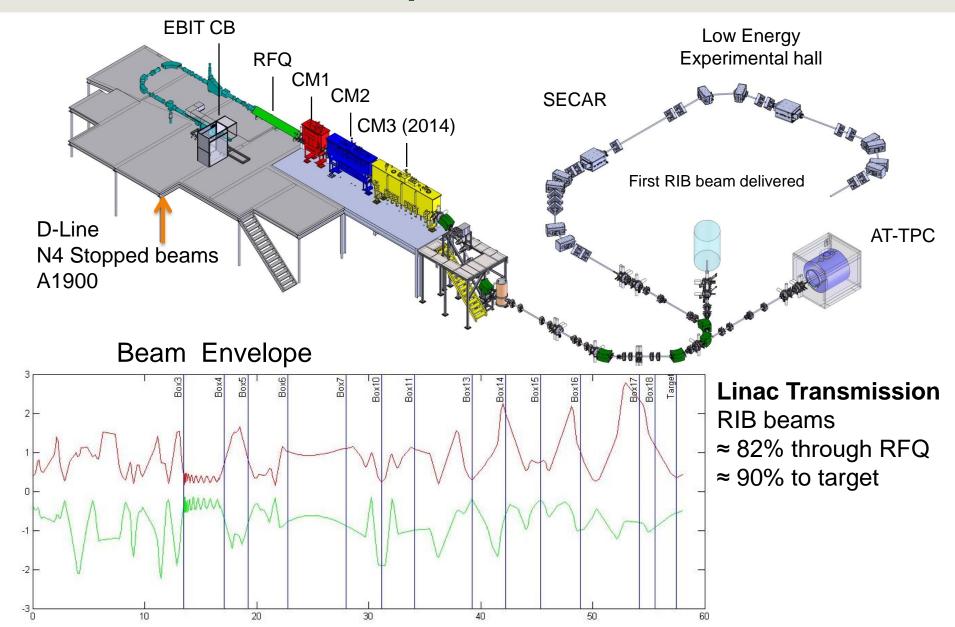


SRF LINAC

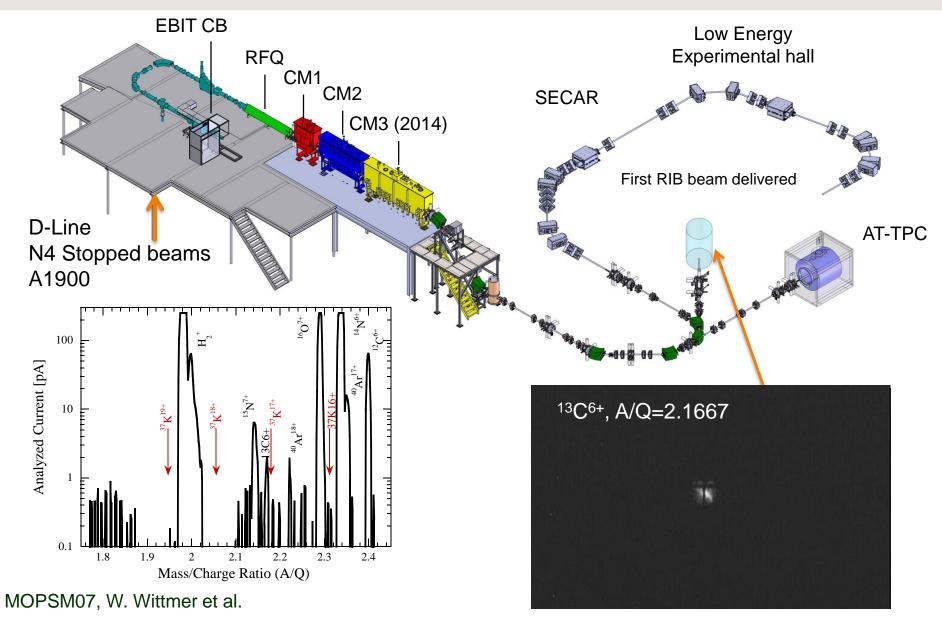
- 80.5 MHz RF frequency
- Flexible energy range (from deceleration 300 keV/u to maximum linac energy)



ReA Beamline acceleration and transport to experiments



Pilot Beams Are Used To Pre-Tune The Linac (Fixed Velocity Profile Used For Scaling)



Radioactive Ion Beam Measured at the experimental end station

